

Enhancing electrical properties by in-situ controlled nanocrystallization of V₂O₅-TeO₂ glass

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Supplementary Information

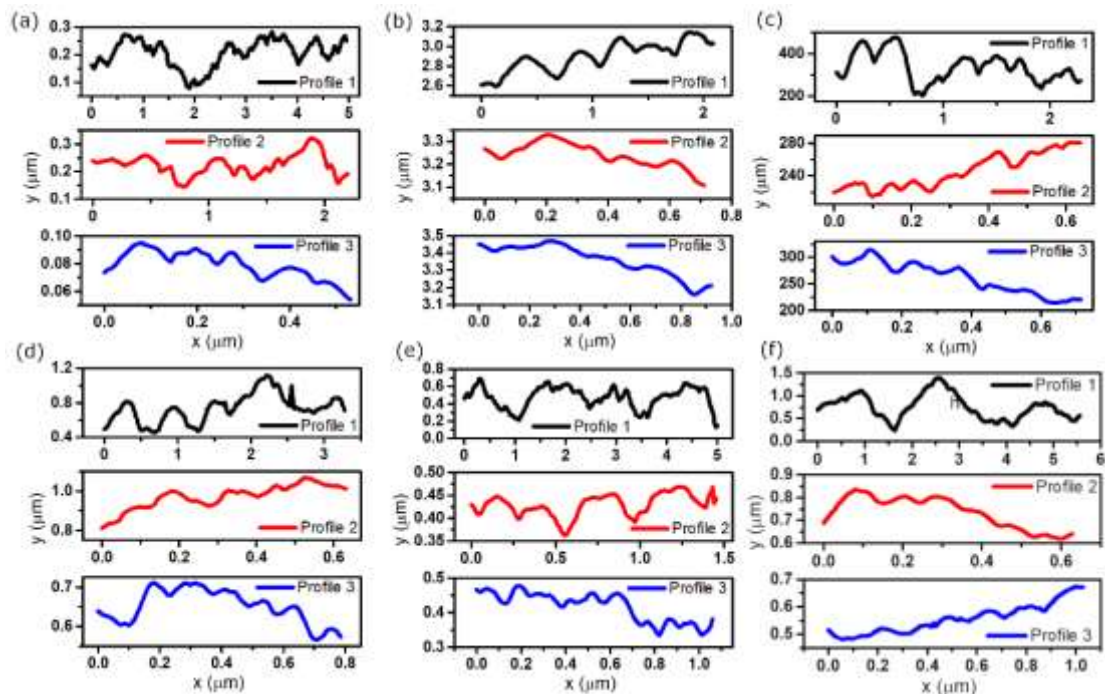


Figure S-1 High profiles obtained as shown in the Fig. 5. of samples (a) 250C, (b) 265C, (c) 270C, (d) 275, (e) 280C, and (f) 285C.

Table S-1. Sizes of agglomerates obtained from the height of observed granules in high profile as shown in Fig.

S-1 (f).

	Grain size (nm)					
250C						
profile 1	40	26	40	8	6	19
profile 2	37	43	25	13	30	10
profile 3	18	14	3	8	9	1
265C						
profile 1	294	272	294	57	60	222
profile 2	39	55	20	24	12	
profile 3	24	4	35	4	15	
270C						
profile 1	168	113	97	73	55	135
profile 2	15	14	11	19	10	6
profile 3	25	17	10	9	7	11
275C						
profile 1	294	279	327	447		
profile 2	80	72	56	58		
profile 3	28	25	10	12	20	
280C						
profile 1	460	413	283	340	453	
profile 2	39	27	81	46	9	
profile 3	50	18	36	27	8	14
285C						
profile 1	866	1152	39	111	482	
profile 2	57	31	28	26	10	
profile 3	12	23	21	5	20	